

Optimization of Urea-EnFET Based on Ta₂O₅ Layer with Post Annealing

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1. Introduction

Enzymatic field effect transistors (EnFETs) have been proposed as an attractive sensing platform for biomedical applications, such as penicillin, urea, glucose, etc [1]. The basements of EnFETs are usually pH ion sensitive field effect transistors (ISFETs). Many materials have been applied for the sensing membrane of pH-ISFETs, in these materials Ta₂O₅ layer has the largest surface buffer capacity (β). In addition, wide applicable pH range (from pH -7 to 13.7) and high chemical resistance for the cleaning-in-place (CIP) test are the attractive advantages of Ta₂O₅ layers as a pH sensing membrane [2, 3]. Since Ta₂O₅ layer is a good sensing membrane for ISFET application, to minimize the light induced drift become subjects in many laboratories.

In this study, the sensing properties of the Ta₂O₅-ISFETs without and with post annealing were described. In addition, to concern about the biomedical application, the urease was immobilized on ISFETs with covalent bonding and compare with standard Si₃N₄-ISFET.

2. Experimental

The ISFETs were fabricated by Institute of Electron Technology (ITE), Poland. The structure and cross section are shown in Fig. 1. The ISFETs are designed with *p*-well arrangement on 3 inch (100) *n*-type wafers. The ratio of channel width and length was $W/L = 600/16$ (in μm). The 50 nm-thick buffering oxide layers were deposited by dry oxidation. The sensing membranes, Ta₂O₅ layers were deposited by rf sputtering, and a post annealing in N₂ ambient for 900°C was performed as the best condition.

The procedures of covalent bonding were described as follows. At first, the surfaces of the sensing membrane were oxidized with H₂O₂ over night. Then, the pretreated surfaces were immersed in 9% APTS for 1 hour. Afterwards, these surfaces were immersed in 10% glutaraldehyde solution for 1 hour. Finally, ureases (E.C. 3.5.1.5) were immobilized on the surfaces. To avoid the deviation caused by the non-attached enzyme, the device was rinsed by phosphate buffer after final step. (Fig. 2)

To evaluate the performance of ISFETs and EnFETs, the $I_{\text{DS}}-V_{\text{GS}}$ curves were measured by HP 4156, firstly. Afterwards, a constant drain-source voltage and constant drain-source current (CVCC) circuit (Fig. 3) was preferred in measurements with $I_{\text{DS}} = 100 \mu\text{A}$ and $V_{\text{DS}} = +0.5 \text{ V}$. Commercial pH buffer solutions from pH 2 to pH 12 were used for the pH sensing properties. For the light induced drift, the intensity of light source was controlled from 1500 lux to 4500 lux. The sensitivity of urea concentrations

were measured from 1 to 10 mM, which with a set of urea concentration variation in 5mM phosphate buffer at pH 6.

3. Results and discussion

At first, the $I_{\text{DS}}-V_{\text{GS}}$ curves of Ta₂O₅-ISFET measured in the buffer solutions from pH 2 to pH 12 are shown in Fig. 4. The I-V curves shifted to the left-side when the ISFETs were measured in buffer solutions of high pH values. The pH response is shown in the inset of Fig. 4. Afterwards, the sensing properties including sensitivity, hysteresis, and drift were measured by CVCC circuit. The results of ISFETs without and with post annealing were listed in Table I, in addition, the results of standard Si₃N₄-ISFET was also included. In this table, the ISFETs with annealed Ta₂O₅ layer showed a near Nernstian response and best response. To find out the mechanism of improved sensing properties, SEM and XPS spectra were analyzed as shown in Fig 5 and Fig 6, respectively. In these two figures, the increase of surface roughness and oxygen intensity could be the reason for the better properties. Moreover, the light induced drift was shown in Fig. 7. The low response was observed on the Ta₂O₅-ISFET with post annealing.

For the urea monitoring by EnFET, a similar $I_{\text{DS}}-V_{\text{GS}}$ curves and transconductance were observed before and after urease immobilization as shown in Fig. 8. The urea response of output voltage to time variation is shown in Fig. 9. The higher concentration was testing, the more intense reaction was performed. In all concentrations, the output voltage was stable in 2 min. The phenomenon could also observed in Fig. 10. Fig. 11 shows the pC_{urea} sensitivity of EnFETs with different pH sensing membrane. In all cases, the linearity is over 99% between 1 to 7.5 mM of urea. As expected, the EnFET with annealed Ta₂O₅ layer shows the best urea response.

4. Conclusion

In this paper, the best pH sensing properties including sensitivity, hysteresis, drift, and light induced drift, were observed on Ta₂O₅-ISFET with post annealing. In addition, the best properties for urea detection were also performed on the EnFET with annealed Ta₂O₅ layer.

Acknowledgements

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References

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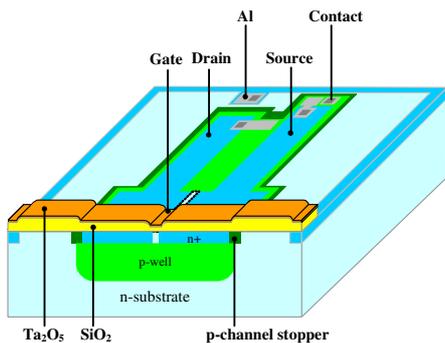


Fig. 1 Structure and cross section of Ta₂O₅-ISFET (ITE, Poland).

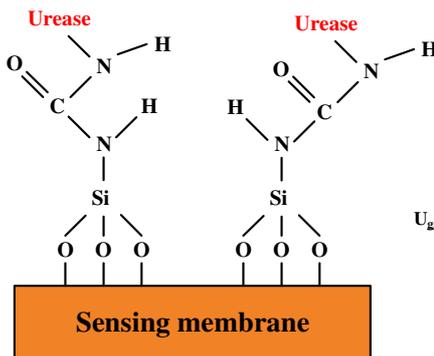


Fig. 2 Schematic of urease immobilized on the top of sensing membrane with covalent bonding.

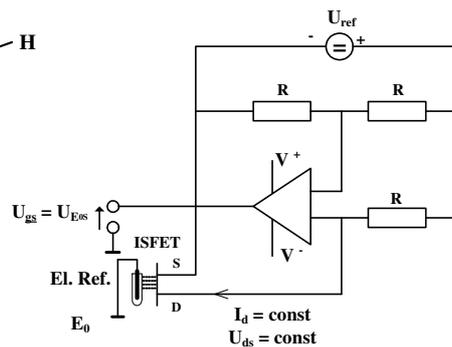


Fig. 3 CVCC circuit of ISFETs and EnFETs.

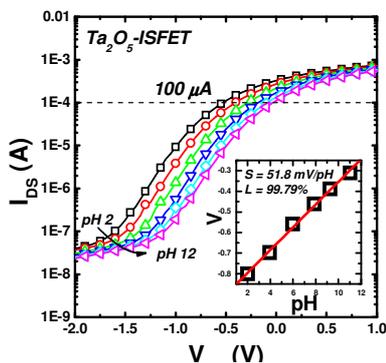


Fig. 4 I_{DS} - V_{GS} curve and sensitivity of Ta₂O₅-ISFET measured from buffer solutions of pH 2 to pH 12.

Table I Sensing properties of ISFETs, with Si₃N₄, Ta₂O₅, and annealed Ta₂O₅ layers

	pH sensitivity (mV/pH)	Hysteresis (7-4-7-10-7) (mV)	Drift (mV/h)
Si ₃ N ₄	51.07	5.1	-0.18
Ta ₂ O ₅	51.83	6.3	-0.43
Ta ₂ O ₅ (anneal)	56.88	0.7	-0.75

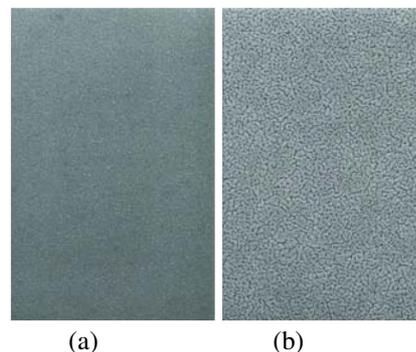


Fig. 5 SEM of Ta₂O₅ layers with (a) amorphous phase and (b) polycrystalline.

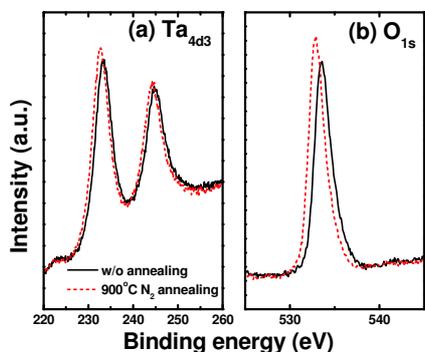


Fig. 6 XPS spectra of (a) Ta_{4d3} and (b) O_{1s} for the Ta₂O₅ layer without and with post annealing.

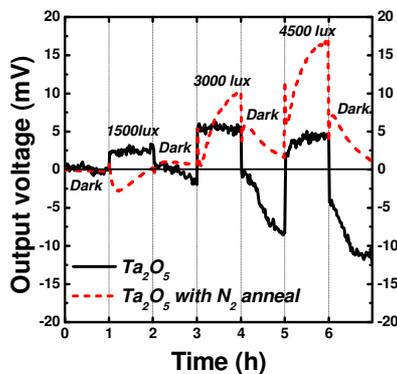


Fig. 7 Light induced drift of Ta₂O₅-ISFET without and with post annealing.

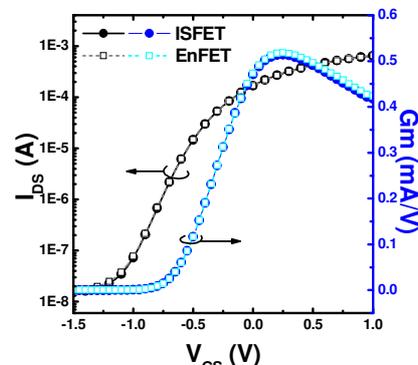


Fig. 8 I_{DS} - V_{GS} curves and G_m of ISFET and EnFET.

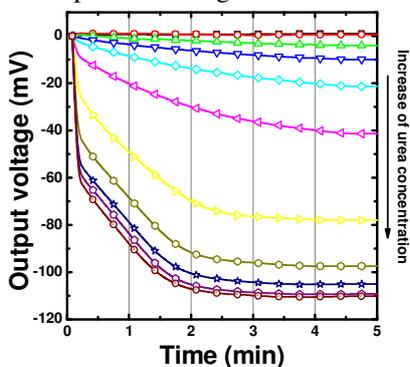


Fig. 9 Response of the output voltage to time variation for the EnFET with different urea concentrations.

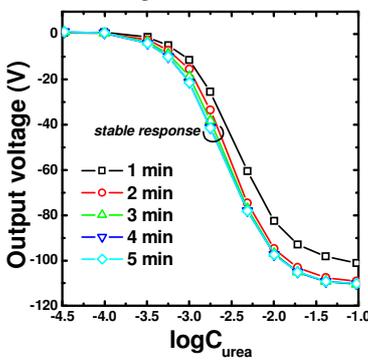


Fig. 10 Output voltage to urea concentrations for the EnFET measured with various time from 1-5 min.

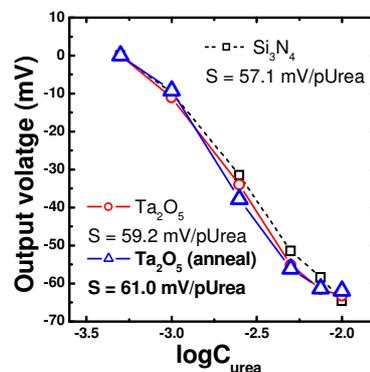


Fig. 11 Urea sensitivity slope of EnFET with Si₃N₄, Ta₂O₅, and annealed Ta₂O₅ layers.